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# **IGBT - Field Stop II**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for UPS and solar applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

#### **Features**

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 5 µs Short-Circuit Capability
- These are Pb-Free Devices

### **Typical Applications**

- Solar Inverters
- Uninterruptible Power Supplies (UPS)
- Welding

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit	
Collector-emitter voltage	V <sub>CES</sub>	650	V	
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	70 35	А	
Diode Forward Current @ Tc = 25°C @ Tc = 100°C	l <sub>F</sub>	70 35	Α	
Diode Pulsed Current T <sub>PULSE</sub> Limited by T <sub>J</sub> Max	I <sub>FM</sub>	120	Α	
Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>CM</sub>	120	Α	
Short–circuit withstand time $V_{GE} = 15$ V, $V_{CE} = 400$ V, $T_J \le +150$ °C	t <sub>SC</sub>	5	μS	
Gate-emitter voltage	$V_{GE}$	±20	V	
Transient gate–emitter voltage (T <sub>PULSE</sub> = 5 $\mu$ s, D < 0.10)		±30	V	
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	300 150	W	
Operating junction temperature range	TJ	–55 to +175	°C	
Storage temperature range	T <sub>stg</sub>	-55 to +175	°C	
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C	

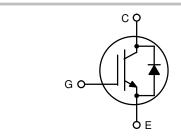
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

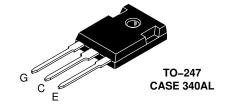


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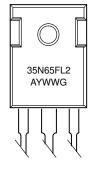
www.onsemi.com

35 A, 650 V V<sub>CEsat</sub> = 1.70 V E<sub>OFF</sub> = 0.28 mJ





#### **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping
NGTB35N65FL2WG	TO-247 (Pb-Free)	30 Units / Rail

#### THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.50	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	1.00	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•	•		•	•	•
Collector–emitter breakdown voltage, gate–emitter short–circuited	$V_{GE} = 0 \text{ V, I}_{C} = 500  \mu\text{A}$	V <sub>(BR)CES</sub>	650	_	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 35 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 35 A, T <sub>J</sub> = 175°C	V <sub>CEsat</sub>	1.50 -	1.70 2.20	2.00	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 350 \mu A$	$V_{GE(th)}$	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}$ $V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}, T_{J=175^{\circ}\text{C}}$	I <sub>CES</sub>	_ _	- -	0.5 4.0	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	-	200	nA
DYNAMIC CHARACTERISTIC					-	-
Input capacitance		C <sub>ies</sub>	-	3115	_	pF
Output capacitance	$V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	C <sub>oes</sub>	-	149	-	1
Reverse transfer capacitance	1	C <sub>res</sub>	-	88	-	1
Gate charge total		$Q_g$	_	125	-	nC
Gate to emitter charge	$V_{CE} = 480 \text{ V}, I_{C} = 35 \text{ A}, V_{GE} = 15 \text{ V}$	Q <sub>ge</sub>	_	30	-	1
Gate to collector charge	1	Q <sub>gc</sub>	_	63	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD			•	•	-
Turn-on delay time		t <sub>d(on)</sub>	_	72	_	ns
Rise time	1	t <sub>r</sub>	_	40	_	
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	_	132	_	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 35 \text{ A}$ $R_{g} = 10 \Omega$	t <sub>f</sub>	_	75	_	
Turn-on switching loss	$V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	_	0.84	_	mJ
Turn-off switching loss	1	E <sub>off</sub>	-	0.28	_	
Total switching loss	1	E <sub>ts</sub>	_	1.12	_	
Turn-on delay time		t <sub>d(on)</sub>	_	70	_	ns
Rise time	1	t <sub>r</sub>	_	38	_	
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	_	135	_	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 35 \text{ A}$ $R_{q} = 10 \Omega$	t <sub>f</sub>	_	96	_	
Turn-on switching loss	$V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	_	1.05	_	mJ
Turn-off switching loss	1	E <sub>off</sub>	_	0.50	_	
Total switching loss	1	E <sub>ts</sub>	_	1.55	_	
DIODE CHARACTERISTIC	•	•				
Forward voltage	$V_{GE} = 0 \text{ V, } I_F = 35 \text{ A}$ $V_{GE} = 0 \text{ V, } I_F = 35 \text{ A, } T_J = 175^{\circ}\text{C}$	V <sub>F</sub>	1.50 -	2.20 2.25	2.90 -	V
Reverse recovery time	$T_J = 25^{\circ} C$ $I_F = 35 \text{ A, } V_R = 200 \text{ V}$ $di_F/dt = 200 \text{ A/}{\mu}\text{s}$	t <sub>rr</sub>	-	68	-	ns
Reverse recovery charge		Q <sub>rr</sub>	-	265	-	nC
Reverse recovery current		I <sub>rrm</sub>	_	7	_	Α
Reverse recovery time	T <sub>.1</sub> = 175°C	t <sub>rr</sub>	-	156	_	ns
Reverse recovery charge	$I_F = 35 \text{ A}, V_R = 400 \text{ V}$	Q <sub>rr</sub>	-	836	-	nC
Reverse recovery current	di <sub>F</sub> /dt = 200 A/μs	I <sub>rrm</sub>	_	8.43	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**

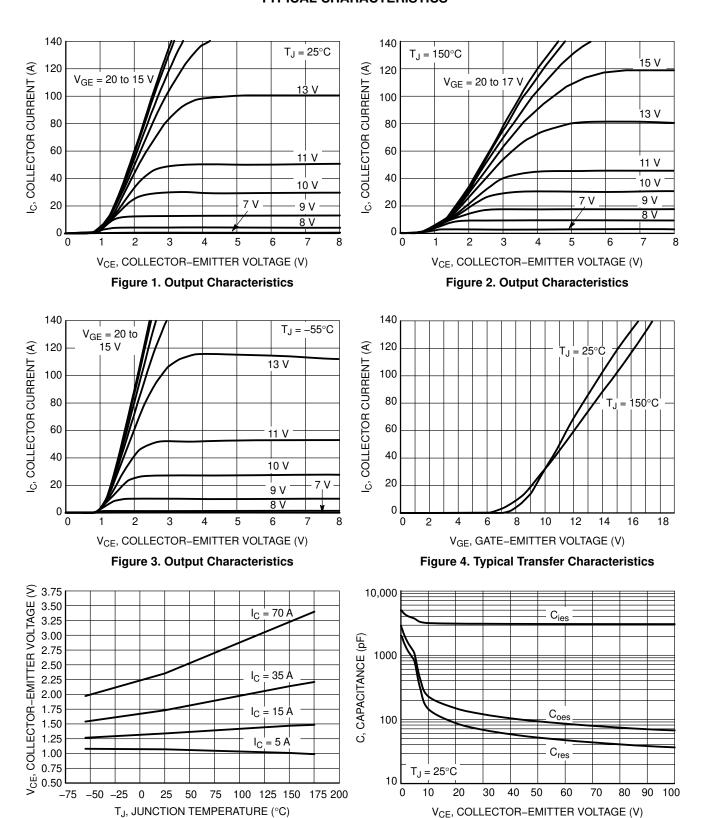
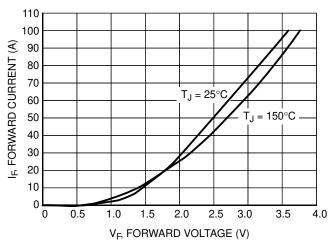


Figure 6. Typical Capacitance

Figure 5. V<sub>CE(sat)</sub> vs. T<sub>J</sub>

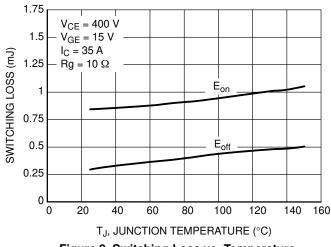
#### **TYPICAL CHARACTERISTICS**



20 V<sub>GE</sub>, GATE-EMITTER VOLTAGE (V) 18 16 14 12 10 8 6 V<sub>CE</sub> = 480 V V<sub>GE</sub> = 15 V 2  $I_{\rm C} = 35 \, {\rm A}$ 0 | 0 20 40 60 80 100 120 140 Q<sub>G</sub>, GATE CHARGE (nC)

Figure 7. Diode Forward Characteristics

Figure 8. Typical Gate Charge



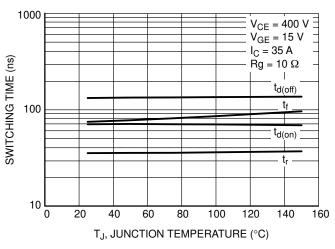
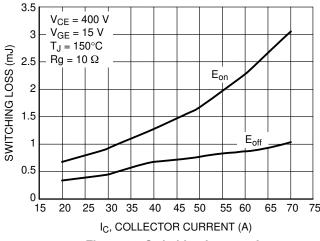


Figure 9. Switching Loss vs. Temperature

Figure 10. Switching Time vs. Temperature



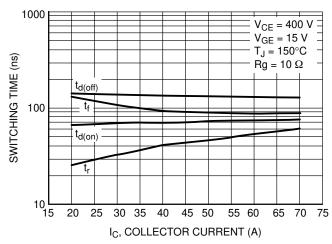


Figure 11. Switching Loss vs. I<sub>C</sub>

Figure 12. Switching Time vs. I<sub>C</sub>

#### TYPICAL CHARACTERISTICS

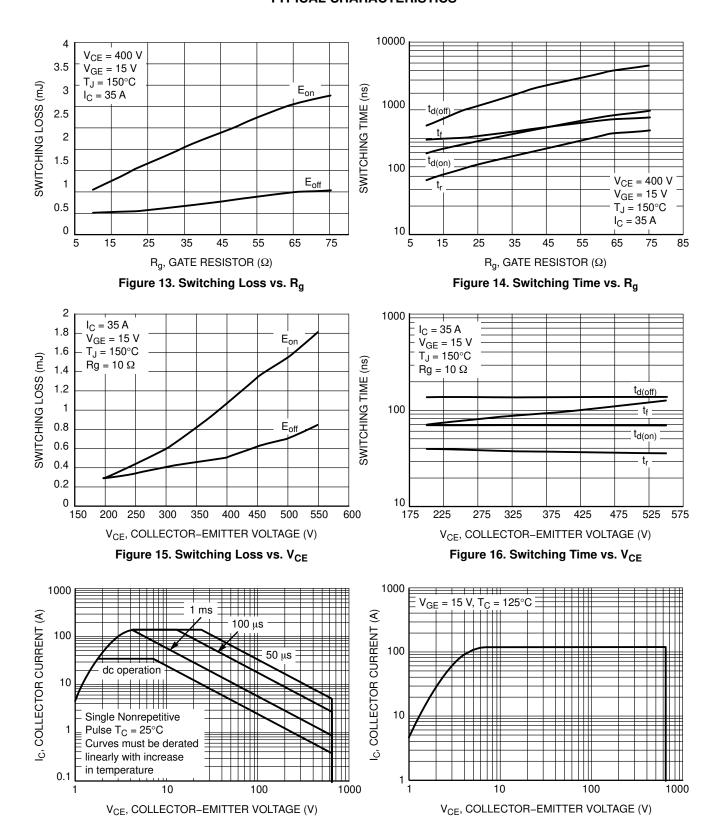
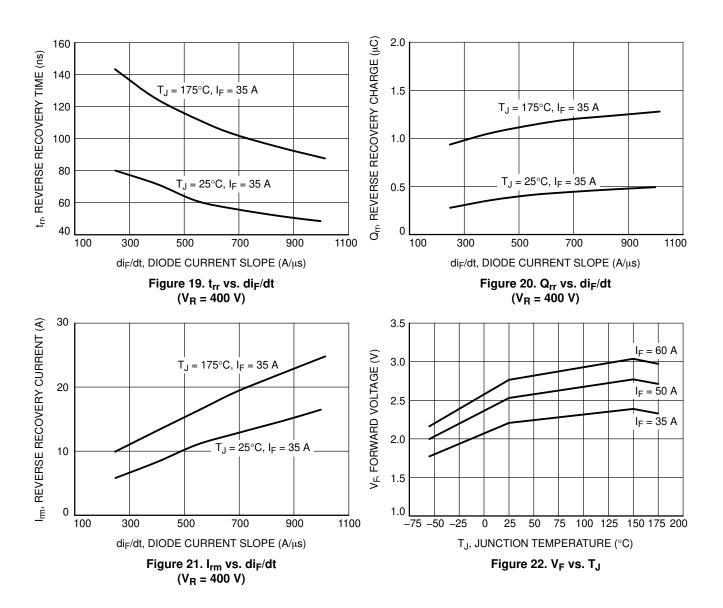


Figure 17. Safe Operating Area

Figure 18. Reverse Bias Safe Operating Area

#### TYPICAL CHARACTERISTICS



#### TYPICAL CHARACTERISTICS

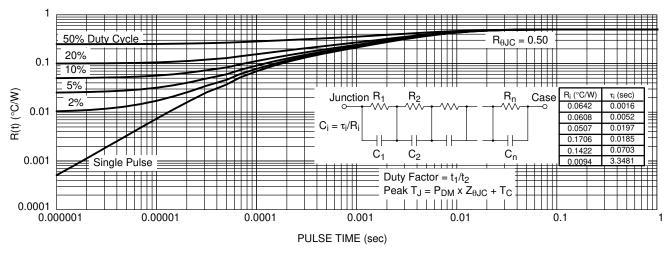


Figure 23. IGBT Transient Thermal Impedance

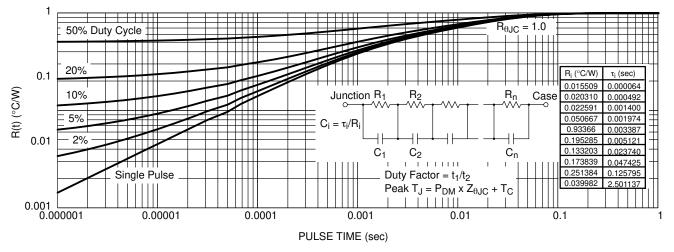
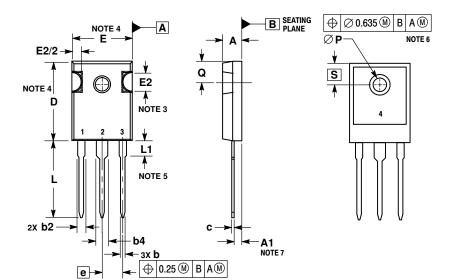


Figure 24. Diode Transient Thermal Impedance

#### PACKAGE DIMENSIONS

TO-247 CASE 340AL **ISSUE B** 



- DIMENSIONING AND TOLERANCING PER ASME Y14.5M. 1994.
- CONTROLLING DIMENSION: MILLIMETERS
- SLOT REQUIRED, NOTCH MAY BE ROUNDED. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
  LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- ØP SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.
  DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

	MILLIMETERS		
DIM	MIN	MAX	
Α	4.70	5.30	
A1	2.20	2.60	
b	1.00	1.40	
b2	1.65	2.35	
b4	2.60	3.40	
С	0.40	0.80	
D	20.80	21.34	
E	15.50	16.25	
E2	4.32	5.49	
е	5.45 BSC		
L	19.80	20.80	
L1	3.81	4.32	
P	3.55	3.65	
Q	5.40	6.20	
S	6.15 BSC		

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